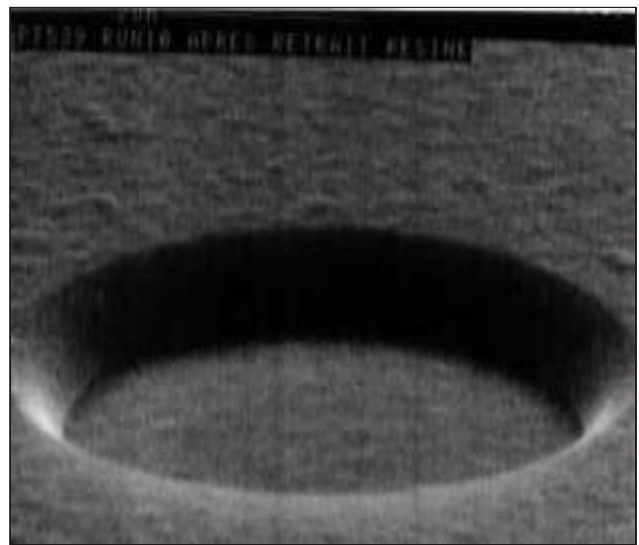
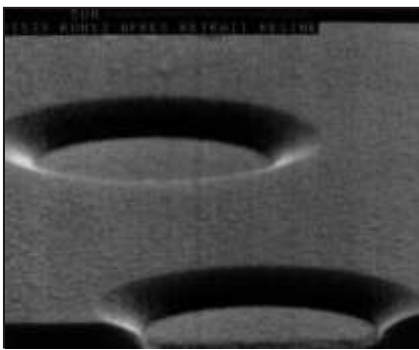
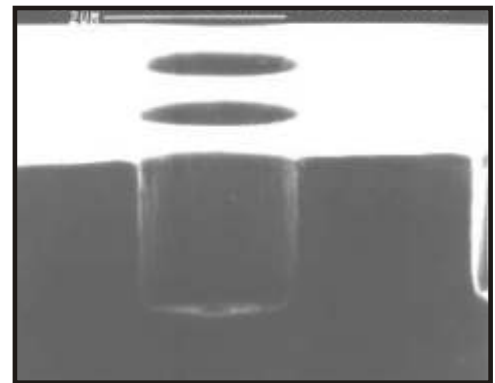
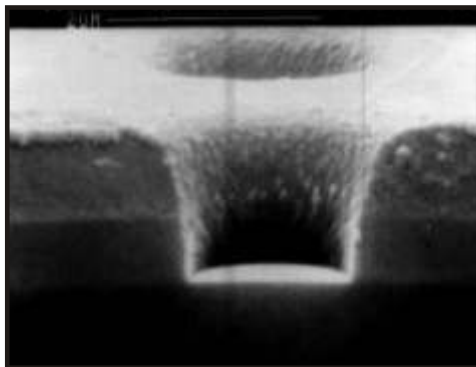


Plasmalab Data

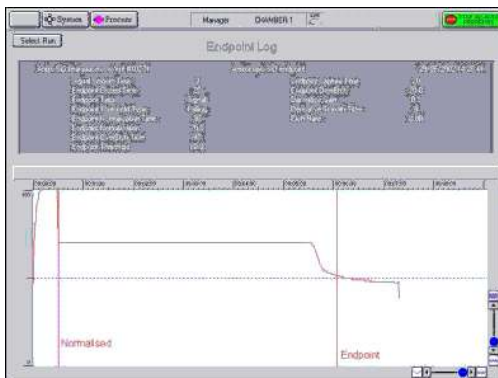
SiO₂ Via Hole Etching



2 µm deep etch of shaped via holes into SiO₂ for reliable metallisation

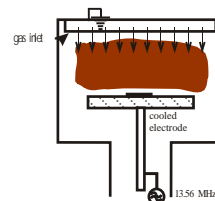


Anisotropic etch:
 PR in place (rhs)
 and removed (lhs)



Signal from optical emission

- Plasmalab 80 Plus*
- Plasmalab 800 Plus*
- Plasmalab System 100*
- Plasmalab System 133*



- Rate : ca. 25 - 100 nm/min*
- Mask: Photoresist
- Selectivity to PR mask: 3 - 10:1
- Selectivity to Si: 8 - 20:1
- Profil: controllable (30° - 90°)
- Uniformity: +/- 3 %

*High rates require Helium cooling, if a PR mask is used.
 Even higher rates are possible with hard masks.